

Search Notes 	Application/Control No.	Applicant(s)/Patent under Reexamination
	10/057,179	MA ET AL.
	Examiner	Art Unit
	Jason M. Perilla	2611

SEARCHED

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
East USPAT/USPGPUB EPO/JPO	6/30/2005	JP
Inventor Name Search East/EDAN	6/30/2005	JP
IEEE Iterative AND channel AND estimate	6/30/2005	JP

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
375	229	6/30/2006	JP
	230	6/30/2006	JP
	232	6/30/2006	JP